SDLS010 - MARCH 1973 - REVISED MARCH 1988

- Fully Buffered to Offer Maximum Isolation from External Disturbance
- Package Options Include Ceramic Carriers and Flat Packages in Addition to Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

description

These devices contain two independent J-K negative-edge-triggered flip-flops. A low level at the preset and clear inputs sets or resets the outputs regardless of the levels of the other inputs. When preset and clear are inactive (high), data at the J and K inputs meeting the setup time requirements are transferred to the outputs on the negative-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold time interval, data at the J and K inputs may be changed without affecting the levels at the outputs. These versatile flip-flops can perform as toggle flip-flops by tying J and K high.

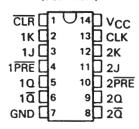
The SN54LS114A and SN54S114 are characterized for operation over the full military temperature range of -55°C to 125°C. The SN74LS114A and SN74S114A are characterized for operation from 0°C to 70°C.

FUNCTION TABLE

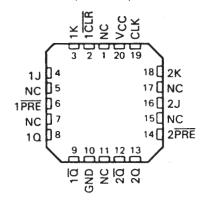
	IN	PUTS			OUT	PUTS
PRE	CLR	CLK	J	K	Q	ā
L	Н	Х	×	X	Н	L
н	L	X	×	X	L	н
L	Ĺ	×	X	X	Н [†]	, H [†]
н	Н	1	L	L	ao	\overline{a}_0
н	н	1	Н	L	н	L
H	H	1	L	Н	L	Н
н	Н	1	Н	Н	TOGGLE	
Н	н	Н	X	X	a_0	\overline{a}_0

[†] The output levels in this configuration are not guaranteed to meet the minimum levels for V_{OH} if the lows at preset and clear are near V_{IL} minimum. Furthermore, this configuration is nonstable; that is, it will not persist when either preset or clear returns to its inactive (high) level.

SN54LS114A, SN54S114 . . . J OR W PACKAGE SN74LS114A, SN74S114A . . . D OR N PACKAGE (TOP VIEW)

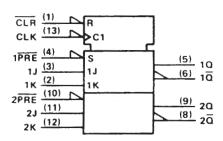


SN54LS114A, SN54S114 . . . FK PACKAGE (TOP VIEW)



NC-No internal connection

logic symbol‡

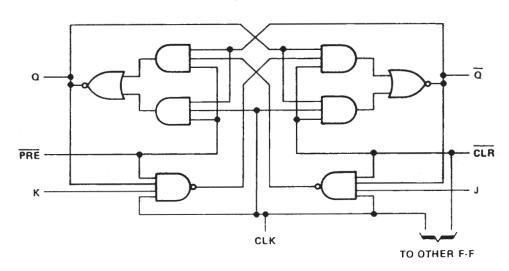


[‡]This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

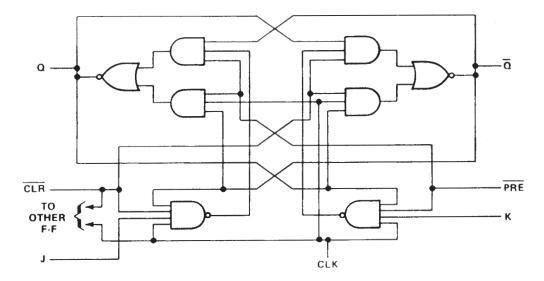
Pin numbers shown are for D, J, N, and W packages.

logic diagram (positive logic)





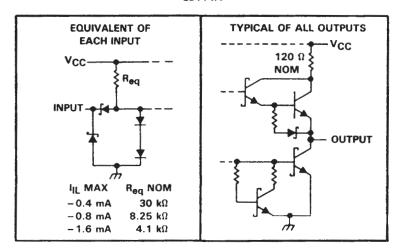
SN54S114, SN74S114A



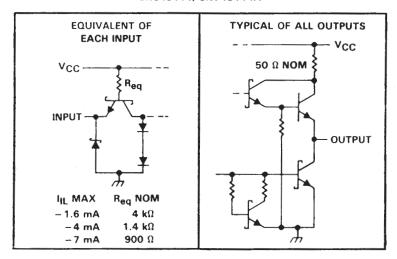
SDLS010 - MARCH 1973 - REVISED MARCH 1988

schematics of inputs and outputs

'LS114A



SN54S114, SN74S114A



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)	7 V
Input voltage: 'LS114A	7 V
SN54S114, SN74S114A	5.5 V
Operating free-air temperature range: SN54'	-55°C to 125°C
SN74'	0°C to 70°C
Storage temperature range	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

SN54LS114A, SN54S114, SN74LS114A, SN74S114A DUAL J-K NEGATIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET, COMMON CLEAR, AND COMMON CLOCK

SDLS010 - MARCH 1973 - REVISED MARCH 1988

recommended operating conditions

			SN	154LS11	4A	SN74LS114A			UNIT
			MIN	NOM	MAX	MIN NOM MA		MAX	UNIT
Vcc	Supply voltage		4.5	5	5.5	4.75	5	5.25	٧
VIH	High-level input voltage		2			2			٧
VIL	Low-level input voltage				0.7			8.0	٧
loн	High-level output current				-0.4			-0.4	mA
lOL	Low-level output current				4			8	mA
fclock	Clock frequency		0		30	0		30	MHz
	Dutan duration	CLK	20			20			ns
tw	Pulse duration	PRE or CLR low	25			25			115
		Data high or low	20	-		20			
t _{su}	Set up time-before CLK↓	CLR inactive	25			25			ns
	PRE inac		20			20			
th	Hold time-data after CLK↓		0			0			ns
TA	Operating free-air temperature		- 55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

		TEGT COMPUTIONS!			SN	154LS11	4A	SN	LIBIT			
PARA	METER	TE	ST CONDITIONS†		MIN	TYP [‡]	MAX	MIN	TYP [‡]	MAX	UNIT	
VIK		V _{CC} = MIN,	I ₁ = -18 mA				- 1.5			- 1.5	V	
Vон		$V_{CC} = MIN,$ $I_{OH} = -0.4 \text{ mA}$	V _{IH} = 2 V,	VIL = MAX,	2.5	3.4		2.7	3.4	-	٧	
		V _{CC} = MIN, I _{OL} = 4 mA	VIL = MAX,	V _{IH} = 2 V,		0.25	0.4		0.25	0.4	V	
V _{OL}			V _{IL} = MAX,	V _{IH} = 2 V,					0.35	0.5	v	
	J or K		A				0.1			0.1		
	CLR		V _I = 7 V				0.6			0.6	mA	
l ₁	PRE	$V_{CC} = MAX,$ $V_{I} = 7 V$					0.3			0.3	IIIA	
	CLK				0.8			0.8				
	J or K						20			20		
	CLR						120			120	μΑ	
(IH	PRE	V _{CC} = MAX,	$V_1 = 2.7 V$				60			60	μ	
	CLK						160			160		
	J or K						-0.4			-0.4		
	CLR		V 0.4.V				- 1.6			- 1.6	mA	
IIL	PRE	V _{CC} = MAX,	$V_1 = 0.4 \text{ V}$				-0.8			-0.8	""	
	CLK						- 1.6			-1.6		
los§	<u> </u>	V _{CC} = MAX,	See Note 2		- 20		- 100	- 20		- 100	mA	
ICC (T		V _{CC} = MAX,	See Note 3			4	6		4	6	mA	

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

^{3.} With all outputs open, ICC is measured with the Q and Q outputs high in turn. At the time of measurement, the clock input is grounded.



[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25 \,^{\circ}\text{C}$.

Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.

NOTES: 2. For certain devices where state commutation can be caused by shorting an output to ground, an equivalent test may be performed with V_O = 2.25 V and 2.125 V for the '54 family and the '74 family, respectively, with the minimum and maximum limits reduced to one half of their stated values.

SN54LS114A, SN54S114, SN74LS114A, SN74S114A DUAL J-K NEGATIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET, COMMON CLEAR, AND COMMON CLOCK SDLS010 – MARCH 1973 – REVISED MARCH 1988

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25 \,^{\circ}\text{C}$ (see Note 4)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CO	MIN	TYP	MAX	UNIT	
f _{max}					30	45		MHz
^t PLH	70 5 55E OU	0 - 5	$R_{L} = 2 k\Omega$,	$C_L = 15 pF$		15	20	ns
t _{PHL}	CLR, PRE or CLK	Q or Q				15	20	กร

NOTE 4: Load circuit and voltage waveforms are shown in Section 1.

SN54LS114A, SN54S114, SN74LS114A, SN74S114A DUAL J-K NEGATIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET, COMMON CLEAR, AND COMMON CLOCK

SDLS010 - MARCH 1973 - REVISED MARCH 1988

recommended operating conditions

			SN54S114			SN74S114A			
		İ	MIN	NOM	MAX	MIN	NOM	MAX	UNIT
V _C C	Supply voltage		4.5	5	5.5	4.75	5	5.25	٧
VIH	High-level input voltage		2			2			V
VIL	Low-level input voltage				0.8			0.8	V
ЮН	High-level output current				- 1			1	mA
OL	Low-level output current				20			20	mA
<u> </u>		CLK	6			6			
tw	Pulse duration	CLK low	6.5			6.5			ns
***		PRE or CLR low	8			8			
t _{su}	Setup time	Data high or low	7			7			ns
th	Hold time-data after CLK1		0			0			ns
TA	Operating free-air temperature		-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

					SN54S114			St	UNIT		
PARA	METER	Τ	EST CONDITIONS†		MIN	TYP‡	MAX	MIN	TYP [‡]	MAX	ONIT
VIK		V _{CC} = MIN,	I _I = -18 mA				- 1.2			-1.2	V
VoH		V _{CC} = MIN, I _{OH} = -1 mA	V _{IH} = 2 V,	V _{IL} = 0.8 V,	2.5	3.4		2.7	3.4		٧
VOL		V _{CC} = MIN, I _{OL} = 20 mA	V _{1H} = 2 V,	V _{IL} = 0.8 V,			0.5			0.5	٧
11		V _{CC} = MAX,	V _I = 5.5 V				1			1	mA
	J or K	V _{CC} = MAX,	V _I = 2.7 V				50			50	
	CLR						200	_		200	μΑ
lн	PRE						100			100	μ
	CLK						200			200	
	JorK						- 1.6			- 1.6	
	CLR						-14			- 14	mA
HL	PRE	V _{CC} = MAX,	$V_1 = 0.5 \text{ V}$				7			- 7	"
	CLK						- 8			- 8	
los§		V _{CC} = MAX			-40		- 100	- 40		- 100	mA
ICC#		V _{CC} = MAX,	See Note 3			15	25		15	25	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

NOTE 3: With all outputs open, ICC is measured with the Q and \overline{Q} outputs high in turn. At the time of measurement, the clock input is grounded.



 $^{^{\}ddagger}$ All typical values are at $V_{CC} = 5 \text{ V}$, $T_{A} = 25 ^{\circ}\text{C}$.

[§] Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.

[#]Values are average per flip-flop.

SN54LS114A, SN54S114, SN74LS114A, SN74S114A DUAL J-K NEGATIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET, COMMON CLEAR, AND COMMON CLOCK SDLS010 – MARCH 1973 – REVISED MARCH 1988

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25 \,^{\circ}\text{C}$ (see Note 4)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	ТҮР	MAX	UNIT
f _{max}				80	125		MHz
tpLH	PRE or CLR	Q or Q			4	7	ns
	PRE or CLR (CLK high)	- uoru I	2 200 0 0 15		5	7	ns
^t PHL	PRE or CLR (CLK low)		$R_L = 280 \Omega$, $C_L = 15 pF$	pr	5	7	115
tPLH			1		4	7	ns
tPHL	CLK				5	7	ns

NOTE 4: Load circuit and voltage waveforms are shown in Section 1.

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